Wander TDEV Measurements for Inexpensive Oscillator

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Outline

Introduction

- □Measurement setup
- □Measurement results
- Conclusions

- Annex B.1.3.1 of IEEE P802.1AS, D6.2 specifies a wander generation requirement for the free-running LocalClock entity in a time-aware system
- The wander generation is specified in terms of a Time Deviation (TDEV) mask
- □TDEV is the square root of Time Variance (TVAR), which is defined as

$$TVAR(\tau) = \sigma_x^2(\tau) = \frac{1}{6} E\left[\left(\Delta^2 \overline{x} \right)^2 \right]$$
$$= \frac{1}{6n^2} E\left[\left(\sum_{i=1}^n \left(x_{i+2n} - 2x_{i+n} + x_i \right) \right)^2 \right]$$

where

 $\tau = n \tau_0$ = observation interval

 τ_0 = sampling interval

 x_i = measured phase (time) error at the i^{th} sampling time (the units of x_i and $\sigma_x(\tau)$ are the same

DTDEV is estimated from a set of measurements as

$$TDEV(\tau) = \sqrt{\frac{1}{6n^2(N-3n+1)} \sum_{j=1}^{N-3n+1} \left[\left(\sum_{i=j}^{j+n-1} (x_{i+2n} - 2x_{i+n} + x_i) \right)^2 \right]},$$

$$n = 1, 2, \dots, \left\lfloor \frac{N}{3} \right\rfloor$$

where

 $\lfloor y \rfloor$ denotes the floor function, i.e., the greatest integer less than or equal to *y*

 B.1.3.1 of IEEE P802.1AS/D6.2 states that the wander generation TDEV for the LocalClock entity shall not exceed the mask of Table B-1 and Figure B-1, reproduced below



Figure B-1—Wander generation (TDEV) requirement for LocalClock entity

Table B-1 — Wander generation TDEV requirement for LocalClock entity

TDEV limit	Observation interval τ
no requirement	$ au < 0.5 \ s$
2.5t ns	$0.5 \le \tau \le 10 \text{ s}$
no requirement	$ au > 10 \ s$

The measurement interval shall be at least 120 s (i.e., at least 12 times the longest observation interval). The measurement shall be made using a low-pass filter with 3 dB bandwidth of 10 Hz, first-order characteristic, and 20 dB/decade roll-off. The sampling interval τ_0 shall not exceed 1/30 s.

□ It is desirable to check whether the above specification can be met by inexpensive oscillators currently used in consumer router or bridge products (wireless or wired)

This presentation gives measurement results for one such oscillator

Measurement Setup - 1

- □The measurement was made using an Agilent E1725C Time Interval Analyzer
 - Measurement data collected and analyzed using Symmetricom TimeMonitor Analyzer software
 - E1725C has a single shot timing resolution of 50 ps, more than adequate for this test
- □A 10 MHz reference was supplied to the time interval analyzer from a 5071A Cesium clock
- □The measured oscillator was contained in a consumer-grade wireless router product the Netgear WGR614 54 Mbps Wireless Router
 - ■802.11g wireless
 - 4 10/100 Mbit/s Ethernet LAN ports
 - 1 10/100 Mbit/s Ethernet WAN port
 - •The measurements were made on one sample device (i.e., one unit)

The oscillator was accessed by removing the top of the wireless router and using an oscilloscope probe

Measurement Setup - 2

Initially, samples were collected over 50 s at a rate of 2.5 kHz

- Later test used 1000 s measurement interval
- □Timestamps were converted to phase deviation, for the TDEV calculation
- The measured oscillator frequency was approximately 44 MHz



□TDEV result – first 50 s measurement

Passes, though not with a large margin



□TDEV result – second 50 s measurement

Marginally fails



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□TDEV result – 1000 s measurment

Marginally fails



□TDEV result – 1000 s measurment, region of marginal failure

Mask is exceeded by approximately 16%, at 2 s observation interval

Symmetricom TimeMonitor Analyzer (file=Netgear256k_1000s.pan) TDEV; Fo=44.00 MHz; Fs=256.0 Hz; 2009/10/20; 14:40:44 HP E1725 time interval analyzer



□ Frequency measurement over 6 days (note diurnal cycle)



□Frequency measurement over 6 days, detail of final steep increase

•Maximum rate of frequency change is on the order of 1.2×10⁻⁸ /1 min = 2 ×10⁻¹⁰ /s = 0.0002 ppm/s



□Sample temperature and phase error history (red plot is temperature, blue plot is phase error)

 Temperature variation is representative of conditions in lab for previous measurements (temperature does not change by more than 3 – 4 deg C)



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□TDEV result – 6 day measurement interval (observation interval ranged from approximately 15 s to 200 s)

TDEV is within an extrapolation of the requirement



Conclusions

- ❑Measured TDEV is either very close to the mask or marginally fails for observation intervals in the range of approximtely 1 – 3 s
- □For observation intervals less than 0.5 s, measured TDEV is well within the mask
- □For temperature conditions in the lab (slide 16), maximum rate of frequency change is on the order of 0.0002 ppm/s
 - This indicates that the current 802.1AS assumption of 4 ppm/s or 1 ppm/s (assumption 9 of Annex Z) is extremely conservative
- The results are very promising, but indicate that the present TDEV requirement should be increased to allow for margin for observation intervals in the range 1 3 s
 - It appears an increase in the mask by a factor of 2 would suffice, providing the performance for timing transport is acceptable (this must be checked via simulation)